



LIST OF PUBLICATIONS CITED BY APPLICANT	Atty. Docket No. SEL 246		Serial No. 09/812,529			
	Applicant Koichiro TANAKA					
	Filing Date March 20, 2001		Group 2812			
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
NB	5,968,383	10/19/99	Yamazaki et al	219	121.75	10/23/97
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	6,096,581	08/01/00	Zhang et al	438	149	05/02/96
	6,159,777	12/12/00	Takenouchi et al	438	149	10/28/97
	6,261,856 B1	07/17/01	Shinohara et al	438	30	12/10/98
	6,509,212 B1	01/21/03	Zhang et al	438	149	01/26/99
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NB	6,723,590 B1	04/20/04	Zhang et al	438	166	07/13/00
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	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE
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EXAMINER: <i>Michael A. Booth</i>				DATE CONSIDERED: <i>08/20/04</i>		
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
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	2) BONNEL, M. et al, "Polycrystalline Silicon Thin-Film Transistors with Two-Step Annealing Process," IEEE Electron Device Letters, vol. 14, no. 12, pp. 551-553, December, (1993).
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	4) Webster's II New Riverside University Dictionary, (1994).

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